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- 3-State Buffer-Type Noninverting Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- Buffered Control Inputs
- SN74ALS575A and 'AS575 Have Synchronous Clear
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), Standard Plastic (N, NT) and Ceramic (J, JT) 300-mil DIPs, and Ceramic Flat (W) Packages

#### description

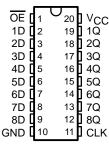
These octal D-type edge-triggered flip-flops feature 3-state outputs designed specifically for bus driving. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight flip-flops enter data on the low-to-high transition of the clock (CLK) input. The SN74ALS575A, SN54AS575, and SN74AS575 may be synchronously cleared by taking the clear (CLR) input low.

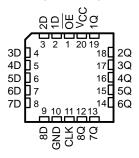
The output-enable  $(\overline{OE})$  input does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS574B, SN54AS574, and SN54AS575 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS574B, SN74ALS575A, SN74AS574, and SN74AS575 are characterized for operation from 0°C to 70°C.

# SN54ALS574B, SN54AS574 . . . J OR W PACKAGE SN74ALS574B, SN74AS574 . . . DW OR N PACKAGE (TOP VIEW)



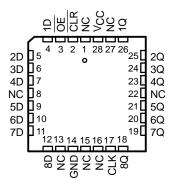
## SN54ALS574B, SN54AS574 . . . FK PACKAGE (TOP VIEW)



#### SN54AS575 ... JT OR W PACKAGE SN74ALS575A, SN74AS575 ... DW OR NT PACKAGE (TOP VIEW)

	_		
CLR [	1	$O_{24}$	v <sub>cc</sub>
OE [		23	] NČ
=	3	22	1Q
2D 🛚	4	21	2Q
	5	20	3Q
4D 🛚	6	19	4Q
5D 🛚	7	18	
6D 🛚	8	17	<b>]</b> 6Q
7D 🛚	9	16	7Q
8D 🛚		15	8Q
NC [	11	14	CLK
GND [	12	13	NC

## SN54AS575 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection



#### **Function Tables**

## SN54ALS574B, SN74ALS574B, SN54AS574, SN74AS574 (each flip-flop)

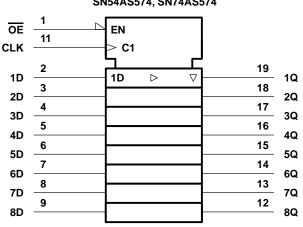
	INPUTS		OUTPUT
OE	CLK	D	Q
L	1	Н	Н
L	$\uparrow$	L	L
L	L	Χ	Q <sub>0</sub>
Н	Χ	Χ	Z

## SN74ALS575A, SN54AS575, SN74AS575 (each flip-flop)

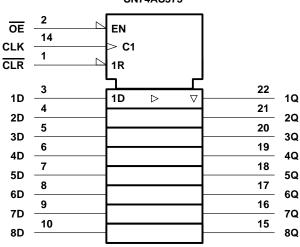
	INP	UTS		OUTPUT
OE	CLR	CLK	D	Q
L	L	1	Х	L
L	Н	$\uparrow$	Н	Н
L	Н	$\uparrow$	L	L
L	Н	L	Х	$Q_0$
Н	Х	Н	Χ	Z

## logic symbols†

#### SN54ALS574B, SN74ALS574B, SN54AS574, SN74AS574



#### SN74ALS575A, SN54AS575, SN74AS575



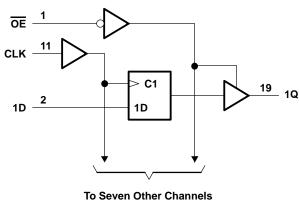
† These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, J, JT, N, and NT packages.



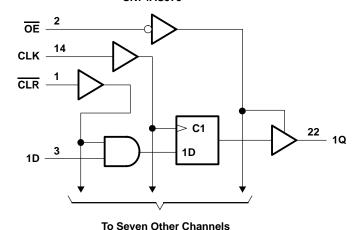
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#### logic diagrams (positive logic)

### SN54ALS574B, SN74ALS574B, SN54AS574, SN74AS574



#### SN74ALS575A, SN54AS575, SN74AS575



Pin numbers shown are for the DW, J, JT, N, and NT packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T <sub>A</sub> : SN54ALS574B	-55°C to 125°C
SN74ALS574B, SN74ALS575A	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

			SN54ALS574B SN74ALS SN74ALS				UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
V <sub>IL</sub>	Low-level input voltage				0.7			0.8	V
ЮН	High-level output current				-1			-2.6	mA
l <sub>OL</sub>	Low-level output current				12			24	mA
٤	Clask fraguency	'ALS574B	0		28	0		35	MHz
fclock	Clock frequency	SN74ALS575A				0		30	IVI⊓∠
	Pulse duration	'ALS574B, CLK high or low	16.5			14			
t <sub>W</sub>	Pulse duration	SN74ALS575A, CLK high or low				16.5			ns
		Data	15			15			
t <sub>su</sub>	Setup time before CLK↑	SN74ALS575A, CLR				15			ns
		Data	4			0			
th	Hold time after CLK↑	SN74ALS575A, CLR				0			ns
TA	Operating free-air temperature		-55		125	0		70	°C



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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	TEST CONDITIONS		4ALS57	'4B	SN74ALS574B SN74ALS575A			UNIT
				MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	
VIK		$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2	2		V <sub>CC</sub> -2	!		
Vон		V <sub>CC</sub> = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.4	3.3					V
		vCC = 4.5 v	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
Vai		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	I <sub>OL</sub> = 24 mA					0.35	0.5	
lozh		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			20			20	μΑ
lozL		$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.4 \text{ V}$			-20			-20	μΑ
l <sub>l</sub>		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA
lіН		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
IIL		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.2			-0.2	mA
lo <sup>‡</sup>		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		11	18		11	18	
	'ALS574B	V <sub>CC</sub> = 5.5 V	Outputs low		17	27		17	27	
			Outputs disabled		17	28		17	28	A
Icc			Outputs high		10	17		10	17	mA
	SN74ALS575A	V <sub>CC</sub> = 5.5 V	Outputs low		15	24		15	24	
			Outputs disabled		16	30		16	30	

#### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)		(   	/ <sub>CC</sub> = 4.5 C <sub>L</sub> = 50 pl R1 = 500 Ω R2 = 500 Ω Γ <sub>A</sub> = MIN 1	<del>=</del> , 2, 2,			UNIT
			SN54AL	S574B	SN74AL	S574B	SN74AL	S575A	
			MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			28		35		30		MHz
<sup>t</sup> PLH	CLK	_	4	22	3	14	4	14	ns
<sup>t</sup> PHL	CLK	Q	4	17	4	14	4	14	115
<sup>t</sup> PZH	<u>OE</u>	_	4	21	3	18	4	18	ns
t <sub>PZL</sub>	OE	Q	4	26	4	18	4	18	110
<sup>t</sup> PHZ	ŌĒ	Q	2	16	1	10	2	10	ns
t <sub>PLZ</sub>	OE .	<u> </u>	2	25	2	12	3	13	115

<sup>§</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. ‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I<sub>OS</sub>.

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T <sub>A</sub> : SN54AS574, SN54AS575	. −55°C to 125°C
SN74AS574, SN74AS575	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

				N54AS57 N54AS57		SN74AS574 SN74AS575			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
$V_{\text{IH}}$	High-level input voltage		2			2			V
$V_{IL}$	Low-level input voltage				8.0			0.8	V
ЮН	High-level output current				-12			-15	mA
loL	Low-level output current				32			48	mA
fclock*	Clock frequency		0		100	0		90	MHz
+ *	Pulse duration	CLK high	5			5.5			ns
t <sub>W</sub> *	Fulse duration	CLK low	4			5.5			115
+ *	O-4 ( h-4 OLK)	Data	3			5.5			ns
t <sub>su</sub> *	Setup time before CLK↑	'AS575, CLR high or low	6.5			6.5			115
+. *		Data	3			3			ns
th*	Hold time after CLK↑	'AS575, CLR	0			0			115
T <sub>A</sub>	Operating free-air temperature		-55		125	0		70	°C

<sup>\*</sup> On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CO	ONDITIONS		154AS57 154AS57		SN SN	UNIT		
				MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	
٧ıĸ		V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I <sub>OH</sub> = −2 mA	V <sub>CC</sub> -2	)		V <sub>CC</sub> -2	)		
Vон		V <sub>CC</sub> = 4.5 V	$I_{OH} = -12 \text{ mA}$	2.4	3.2					V
		VCC = 4.5 V	$I_{OH} = -15 \text{ mA}$				2.4	3.3		
V		V 45V	I <sub>OL</sub> = 32 mA		0.29	0.5				V
VOL		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA					0.34	0.5	V
lozh		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			50			50	μΑ
lozL		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0.4 V			-50			-50	μΑ
II		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA
lн		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
	OE, CLK, CLR	V 55V	V 04V			-0.5			-0.5	Λ
IIL	D	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> =℃!¥′ ∨			-3			-2	mA
I <sub>O</sub> ‡		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	-30		-112	mA
			Outputs high		73	116		73	116	
	'AS574	V <sub>CC</sub> = 5.5 V	Outputs low		85	134		85	134	
l.		1	Outputs disabled		84	134		84	134	
ICC			Outputs high		78	126		78	126	mA
	'AS575	V <sub>CC</sub> = 5.5 V	Outputs low		89	142		89	142	
			Outputs disabled		88	142		88	142	

 $<sup>\</sup>uparrow$  All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C <sub>I</sub> R1 R2 T <sub>A</sub>	= 50 pF = 500 Ω = 500 Ω = MIN t	2, 2, o MAX§		UNIT
				SN54AS574 SN74AS574 SN54AS575 SN74AS575			
			MIN	MAX	MIN	MAX	
f <sub>max</sub> *			100		90		MHz
<sup>t</sup> PLH	CLK	Any O	3	11	3	8	ns
<sup>t</sup> PHL	OLK	Any Q	4	11	4	9	113
<sup>t</sup> PZH	ŌĒ	A O	2	7	2	6	ns
<sup>t</sup> PZL	OE	Any Q	3	11	3	10	113
<sup>t</sup> PHZ	ŌĒ	Any Q	2	7	2	6	ns
<sup>t</sup> PLZ	OE .	Ally Q	2	7	2	6	115

<sup>\*</sup> On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

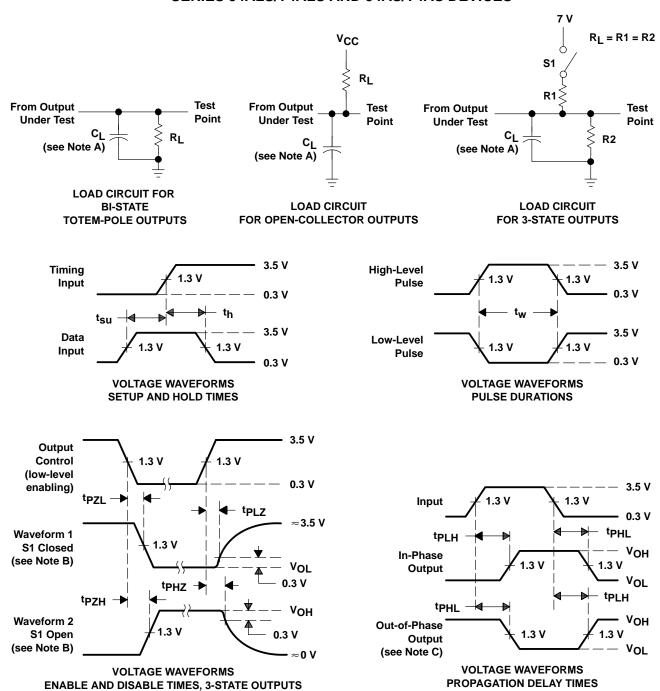


<sup>&</sup>lt;sup>‡</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

<sup>§</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

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## PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz,  $t_f = t_f = 2$  ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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